

3.3V CMOS 16-BIT LATCHED TRANSCEIVER

IDT74FCT163543/A/C

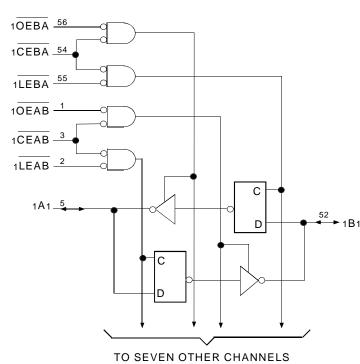
FEATURES:

- 0.5 MICRON CMOS Technology
- Typical tsk(o) (Output Skew) < 250ps
- ESD > 2000V per MIL-STD-883, Method 3015;
 > 200V using machine model (C = 200pF, R = 0)
- 25 mil pitch SSOP, 19.6 mil pitch TSSOP and 15.7 mil pitch TVSOP Packages
- Extended commercial range of -40°C to +85°C
- Vcc = 3.3V ±0.3V, Normal Range or Vcc = 2.7V to 3.6V, Extended Range
- CMOS power levels (0.4µ W typ. static)
- Rail-to-Rail output swing for increased noise margin
- Low Ground Bounce (0.3V typ.)
- Inputs (except I/O) can be driven by 3.3V or 5V components

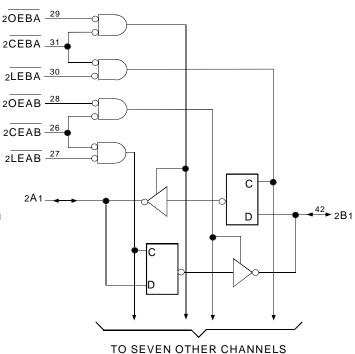
DESCRIPTION:

The FCT163543/A/C 16-bit latched transceivers are built using advanced dual metal CMOS technology. These high-speed, low-power devices are organized as two independent 8-bit D-type latched transceivers with separate input and output control to permit independent control of data flow in either direction. For example, the A-to-B Enable (xCEAB) must be low in order to enter data from the A port or to output data from the B port. xLEAB controls the latch function. When xLEAB is low, the latches are transparent. A subsequent low-to-high transition of xLEAB signal puts the A latches in the storage mode. xOEAB performs output enable function on the B port. Data flow from the B port to the A port is similar but requires using xCEBA, xLEBA, and xOEBA inputs. Flow-through organization of signal pins simplifies layout. All inputs are designed with hysteresis for improved noise margin.

The FCT163543/A/C have series current limiting resistors. These offer low ground bounce, minimal undershoot, and controlled output fall times–reducing the need for external series terminating resistors.



FUNCTIONAL BLOCK DIAGRAM



COMMERCIAL TEMPERATURE RANGE

JULY 1999

1



DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified: Commercial: TA = -40°C to +85°C, Vcc = 2.7V to 3.6V

Symbol	Parameter	Test Conditions ⁽¹⁾	Min.	Тур. ⁽²⁾	Max.	Unit
--------	-----------	--------------------------------	------	---------------------	------	------

POWER SUPPLY CHARACTERISTICS

Symbol	Parameter	Test Conditions	Min.	Тур. ⁽²⁾	Max.	Unit	
Δlcc	Quiescent Power Supply Current TTL Inputs HIGH	$V_{CC} = Max.$ VIN = VCC -0.6V ⁽³⁾		_	2	30	μA
ICCD	Dynamic Power Supply Current ⁽⁴⁾	Vcc = Max., Outputs Open xCEAB and xOEAB = GND xCEBA = Vcc One Input Toggling 50% Duty Cycle	VIN = VCC VIN = GND	_	60	100	μΑ/ MHz
lc	Total Power Supply Current ⁽⁶⁾	Vcc = Max., Outputs Open fi = 10MHz 50% Duty Cycle	VIN = VCC VIN = GND	_	0.6	1	mA
		xLEAB, xCEAB and xOEAB= GND xCEBA = Vcc One Bit Toggling	Vin = Vcc -0.6V Vin = GND	-	0.6	1	
		Vcc = Max., Outputs Open fi = 2.5MHz 50% Duty Cycle	Vin = Vcc Vin = GND	-	2.4	4 ⁽⁵⁾	×
		xLEAB, xCEAB and xOEAB= GND xCEBA = Vcc Sixteen Bits Toggling	Vin = Vcc -0.6V Vin = GND	-	2.4	4.3 ⁽⁵⁾	

NOTES:

1. For conditions shown as max. or min., use appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical values are at Vcc = 3.3V, +25°C ambient.

3. Per TTL driven input; all other inputs at Vcc or GND.

4. This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.

5. Values for these conditions are examples of the Icc formula. These limits are guaranteed but not tested.

6. IC = IQUIESCENT + INPUTS + IDYNAMIC

IC = ICC + DICC DHNT + ICCD (fCPNCP/2 + fiNi)

Icc = Quiescent Current (IccL, IccH and Iccz)

 ΔIcc = Power Supply Current for a TTL High Input

DH = Duty Cycle for TTL Inputs High

NT = Number of TTL Inputs at DH

ICCD = Dynamic Current Caused by an Input Transition Pair (HLH or LHL)

fcp = Clock Frequency for Register Devices (Zero for Non-Register Devices)

NCP = Number of Clock Inputs at fCP

fi = Input Frequency

Ni = Number of Inputs at fi

SWITCHING CHARACTERISTICS OVER OPERATING RANGE (4)

			FCT163543		FCT163543A		FCT163543C		
Symbol	Parameter	Condition ⁽¹⁾	Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	Unit
t PLH	Propagation Delay	CL = 50pF	1.5	8.5	1.5	6.5	1.5	5.3	ns
t PHL	Transparent Mode	$RL = 500\Omega$							
	xAx to xBx or xBx to xAx								
t PLH	Propagation Delay		1.5	12.5	1.5	8	1.5	7	ns
t PHL	xLEBA to xAx, xLEAB to xBx								
tPZH	Output Enable Time		1.5	12	1.5	9	1.5	8	ns
tPZL	xOEBA or xOEAB to xAx or xBx								
	xCEBA or xCEAB to xAx or xBx								
tphz	Output Disable Time		1.5	9	1.5	7.5	1.5	6.5	ns
tPLZ	xOEBA or xOEAB to xAx or xBx								
	xCEBA or xCEAB to xAx or xBx								
tsu	Set-up Time HIGH or LOW		3	—	2	—	2	_	ns
	xAx or xBx to $x\overline{LEAB}$ or $x\overline{LEBA}$								
tн	Hold Time HIGH or LOW		2	—	2	—	2	_	ns
	xAx or xBx to xLEAB or xLEBA								
tw	xLEBA or xLEAB Pulse Width LOW		5	—	5	_	5	_	ns
tsk(o)	Output Skew ⁽³⁾		_	0.5	_	0.5	_	0.5	ns

NOTES:

1. See test circuits and waveforms.

2. Minimum limits are guaranteed but not tested on Propagation Delays.

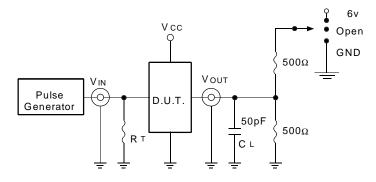
3. Skew between any two outputs of the same package switching in the same direction. This parameter is guaranteed by design.

4. Propagation Delays and Enable/Disable times are with Vcc = 3.3V ±0.3V, Normal Range. For Vcc = 2.7V to 3.6V, Extended Range, all Propagation Delays and Enable/Disable times should be degraded by 20%.

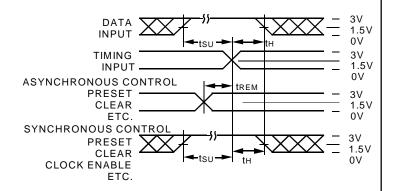
IDT74FCT163543/A/C 3.3V CMOS 16-BIT LATCHED TRANSCEIVER

TEST CIRCUITS AND WAVEFORMS

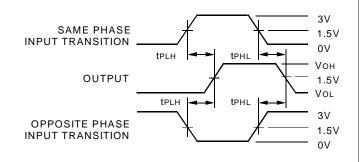
TEST CIRCUITS FOR ALL OUTPUTS



SET-UP, HOLD, AND RELEASE TIMES



PROPAGATION DELAY



SWITCH POSITION

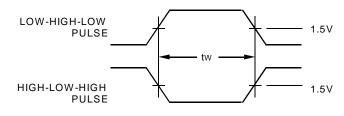
Test	Switch
Open Drain	
Disable Low	6V
Enable Low	
Disable High	GND
Enable High	
All Other Tests	Open
	3v16-link

DEFINITIONS:

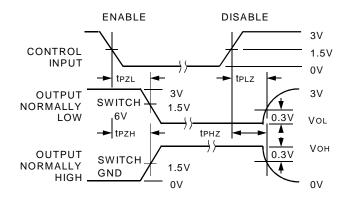
CL = Load capacitance: includes jig and probe capacitance.

RT = Termination resistance: should be equal to ZOUT of the Pulse Generator.

PULSE WIDTH



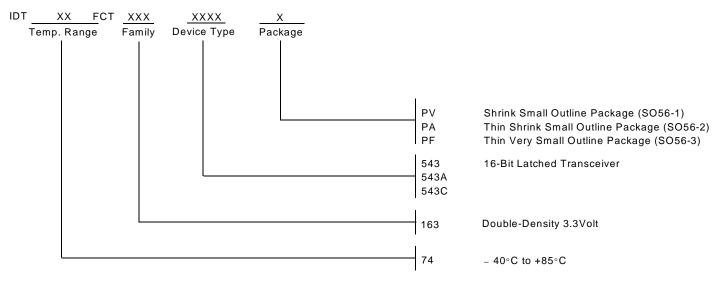
ENABLE AND DISABLE TIMES



NOTES:

- 1. Diagram shown for input Control Enable-LOW and input Control Disable-HIGH.
- 2. Pulse Generator for All Pulses: Rate \leq 1.0MHz; tF \leq 2.5ns; tR \leq 2.5ns.
- 3. If Vcc is below 3V, input voltage swings should be adjusted not to exceed Vcc.

ORDERING INFORMATION





CORPORATE HEADQUARTERS 2975 Stender Way Santa Clara, CA 95054 *for SALES:* 800-345-7015 or 408-727-6116 fax: 408-492-8674 www.idt.com*

*To search for sales office near you, please click the sales button found on our home page or dial the 800# above and press 2. The IDT logo is a registered trademark of Integrated Device Technology, Inc.